

Session

M9: Poster Session

Time: Monday, 17/Sep/2018:5:00pm - 7:00pm

Location: **Poster Area**

Poster Area Physikalisches Institut Wilhelm-Klemm-Str. 10 48149
Münster Germany

Presentations

M9	(Edit Contribution Details, ID: 189)
1	Development of a charge-implicit ReaxFF potential for modelling high-energy collisions in C/H/O systems
Poster	Michal Kanski¹, Dawid Maciazek¹, Barbara J. Garrison², Adri C.T. van Duin³, Zbigniew Postawa¹ ¹ Institute of Physics, Jagiellonian University, Lojasiewicza 11, 30-348 Krakow, Poland; ² Department of Chemistry, Penn State University, 104 Chemistry Building, University Park, Pennsylvania 16802, United States; ³ Department of Mechanical and Nuclear Engineering, Penn State University, University Park, Pennsylvania 16802, United States
M9	(Edit Contribution Details, ID: 172)
2	Impact of the molecular weight on the depth profiling of polymer thin films: case study with low energy Cs⁺ as sputtering primary ion.
Poster	Amal Ben Hadj Mabrouk¹, Marc Veillerot¹, Denis Mariolle¹, Antoine Chateauminois² ¹ Univ. Grenoble Alpes, F-38000 Grenoble, France CEA, LETI, MINATEC Campus, F-38054 Grenoble, France; ² Soft Matter Science and Engineering Laboratory (SIMM), PSL Research University, UPMC Univ Paris 06, ESPCI Paris, CNRS, 10 rue Vauquelin
M9	(Edit Contribution Details, ID: 162)
3	Enhancement of sensitivity for organic fragments and molecules using large gas cluster Laser-SNMS
Poster	Marcel Heeger, Thorsten Adolphs, Bonnie J. Tyler, Andreas Pelster, Heinrich F. Arlinghaus University of Muenster, Germany
M9	(Edit Contribution Details, ID: 190)
4	Metabolic imaging using argon gas cluster ion beams – optimal sputtering conditions for low fragmentation
Poster	Vanina Cristaudo¹, Lidija Matjačić¹, Rasmus Havelund¹, Yulia Panina^{1,2}, Mariia Yuneva², Ian Gilmore¹ ¹ National Centre of Excellence in Mass Spectrometry Imaging, National Physical Laboratory, Hampton Road, Teddington, TW11 0LW, UK; ² Oncogenes and Tumour Metabolism Lab, The Francis Crick Institute, 1 Midland Road, London, NW1 1AT, UK
M9	(Edit Contribution Details, ID: 117)
5	SIMS investigations of formation and unimolecular decay processes of Si_nO_m⁻ clusters under ion sputtering
Poster	Sergey Maksimov^{1,2}, Nariman Dzhemilev², Sergey Kovalenko², Oskar Tukfatullin², Sherali Khozhiev^{2,3} ¹ Institute of Chemistry and Physics of Polymers, Academy of Sciences of the Republic of Uzbekistan, Uzbekistan; ² Arifov Institute of ion-plasma and laser technologies, Academy of Sciences of the Republic of Uzbekistan; Uzbekistan; ³ Tashkent State Technical University named after Islam Karimov
M9	(Edit Contribution Details, ID: 224)
6	IMPLANTATION ON Si AND SiO_x BY LOW ENERGY CESIUM IONS
Poster	Utkir Sharopov, Bakhtiyar Atabaev, Ruzmat Djabbarganov, Feruz Khudayqulov, Ikrom Mirzakhmedov Ion plazma & lazer Technology Institute, Uzbekistan
M9	(Edit Contribution Details, ID: 173)
7	Influence of deformation fields on the sputtering rate in AlN/GaN superlattices
Poster	Tomash Sabov, Oleksandr Dubikovskiy, Oleksandr Kosulya, Oleksii Liubchenko Lashkarev Institute of Semiconductor Physics NAS of Ukraine
M9	(Edit Contribution Details, ID: 160)
8	Influence of the substrate temperature on the ionization probability
Poster	Yannik Moryson, Marcus Rohnke Justus-Liebig-Universität Gießen, Germany
M9	(Edit Contribution Details, ID: 116)
9	Thermal effects in low energy ion irradiation of solids
Poster	Yuriy Kudriavtsev CINVESTAV-IPN, Mexico

(Edit Contribution Details, ID: 175)

The conductivity of polymer layered systems modified with halogen salts of d-type metals.

M9	10	Poster	<p>Paweł Mateusz Dąbczyński¹, Agnieszka Pawłowska¹, Magdalena Ceglarska¹, Anna Dłubacz¹, Mateusz Marek Marzec², Anna Majcher¹, Wojciech Tomczyk¹, Monika Marzec¹, Andrzej Bernasik^{2,3}, Andrzej Budkowski¹, Jakub Rysz¹</p> <p>¹M. Smoluchowski Institute of Physics, Jagiellonian University, Łojasiewicza 11, 30-348 Kraków, Poland; ²Academic Centre for Materials and Nanotechnology, AGH University of Science and Technology, al. Mickiewicza 30, 30-049 Kraków, Poland; ³Faculty of Physics and Applied Computer Science, AGH University of Science and Technology, al. Mickiewicza 30, 30-049 Kraków, Poland</p>
M9	11	Poster	<p>(Edit Contribution Details, ID: 168)</p> <p>Study of organic samples using ME-SIMS prepared with a Knudsen-type matrix coater</p> <p>Thorsten Adolphs, Martin Körsgen, Bonnie J. Tyler, Marcel Heeger, Heinrich F. Arlinghaus University of Muenster, Germany</p>
M9	12	Poster	<p>(Edit Contribution Details, ID: 208)</p> <p>Preliminary performance results for a new UHV SIMS, 'High5', with simultaneous positive and negative SIMS & ICP oxygen plasma source</p> <p>Richard John Chater¹, Sarah Fearn¹, Graham Cooke², Noel Smith³, Ainara Aguadero¹</p> <p>¹Imperial College London, United Kingdom; ²Hidden Analytical Ltd, Warrington, United Kingdom; ³Oregon-Physics, Beaverton, OR 97006, USA</p>
M9	13	Poster	<p>(Edit Contribution Details, ID: 237)</p> <p>Ion-beam sectioning, nano-scale 3D material reconstruction and 'in-operando' processing in a UHV dual SIMS detector ion microscope</p> <p>Richard John Chater¹, Sarah Fearn¹, Ainara Aguadero¹, Graham Cooke², Noel Smith³</p> <p>¹Imperial College London, United Kingdom; ²Hidden Analytical, Warrington, United Kingdom; ³Oregon Physics, Beaverton, Oregon, USA</p>
M9	14	Poster	<p>(Edit Contribution Details, ID: 132)</p> <p>Latest Developments in Cluster Beam Technology for ToF SIMS: Towards Greater Spatial Resolution, Improved Ion Yields, and Faster Etch Rates!</p> <p>Allen Bellew, Paul Blenkinsopp Ionoptika Limited, United Kingdom</p>
M9	15	Poster	<p>(Edit Contribution Details, ID: 146)</p> <p>III-V compound analysis using the CAMECA IMS 7f-Auto</p> <p>Paula Peres¹, Seo-Youn Choi¹, François Desse¹, Shiro Miwa²</p> <p>¹CAMECA France; ²CAMECA Japan</p>
M9	16	Poster	<p>(Edit Contribution Details, ID: 223)</p> <p>A correlative study of implanted FDSOI by TOF-SIMS and MEIS</p> <p>François Pierre¹, Lucien Penlap Woguia¹, Denis Jalabert², Jean-Paul Barnes¹</p> <p>¹Univ. Grenoble Alpes, CEA, LETI, DTSI, SCMC, F-38000 Grenoble.; ²Univ. Grenoble Alpes, CEA, INAC, MEM, LEMMA, F-38000 Grenoble.</p>
M9	17	Poster	<p>(Edit Contribution Details, ID: 217)</p> <p>DIFFUSION OF DEFECTS TO SURFACE AT CLEANING SILICON WAFERS</p> <p>Utkir Sharopov, Bakhtiyar Atabaev, Ruzmat Djabbarganov, Feruz Khudayqulov, Ikrom Mirzakhmedov Ion plazma & lazer Technology Institute, Academy of Sciences of the Republic of Uzbekistan, Tashkent</p>
M9	18	Poster	<p>(Edit Contribution Details, ID: 105)</p> <p>Novel p-type anodic NiO sponges for photocatalytic applications</p> <p>Benedikt F. Winhard, Farzaneh Ahmadloo, Manuela S. Killian Friedrich-Alexander University, Erlangen, Germany</p>
M9	19	Poster	<p>(Edit Contribution Details, ID: 177)</p> <p>ToF-SIMS analysis of meso-porous silicon samples: surface modifications and chemical response changes when exposed to different ions beams</p> <p>Marc Veillerot, Riccardo Scarazzini, Vincent Jousseau, Frédéric Gaillard Univ. Grenoble Alpes, CEA, LETI, DTSI, SCMC, F-38000 Grenoble</p>
M9	20	Poster	<p>(Edit Contribution Details, ID: 231)</p> <p>Temperature-dependent SIMS depth profiling of InGaN multilayers</p> <p>Juraj Karlovský^{1,2}, Michal Potoček^{1,2}, Petr Bábora^{1,2}</p> <p>¹Institute of Physical Engineering, Faculty of Mechanical Engineering, Brno University of Technology, Technická 2896/2, Brno, 616 69, Czech Republic; ²CEITEC - Central European Institute of Technology, Brno University of Technology, Brno, 616 00, Czech Republic</p>
M9	21	Poster	<p>(Edit Contribution Details, ID: 180)</p> <p>SIMS measurements of InAs/InAsSb type II superlattice</p> <p>Urszula Chodorow¹, Paweł Piotr Michałowski², Krystian Michałczewski^{1,3}, Piotr Martyniuk¹</p> <p>¹Military University of Technology, Poland; ²Institute of Electronic Materials Technology, Poland; ³VIGO SYSTEM S.A., Poland</p>

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M9	22	Poster	<p>Accurate determination of matrix composition of topological insulator $Pb_{1-x}Sn_xSe$ by SIMS</p> <p>Rafal Jakiela¹, Marta Galicka¹, Piotr Dziawa¹, Gunther Springholz³, Adam Barcz^{1,2}</p> <p>¹Institute of Physics, Polish Academy of Sciences, Poland; ²Institute of Electron Technology, Poland; ³Institute for Semiconductor and Solid State Physics, Johannes Kepler Universität, Austria</p>
M9	23	Poster	<p>(Edit Contribution Details, ID: 254)</p> <p>Real 3D depth profiling of heterogeneous microelectronic structures using a combined ToF-SIMS/<i>in-situ</i> SPM tool.</p> <p>Alexis Franquet¹, Valentina Spampinato¹, Wilfried Vandervorst^{1,2}, Paul van der Heide²</p> <p>¹imec, Belgium; ²Instituut voor Kern- en Stralingsfysica, K. U. Leuven, Leuven, Belgium.</p>
M9	24	Poster	<p>(Edit Contribution Details, ID: 165)</p> <p>3D-Imaging of $Cu(In,Ga)Se_2$ Grain Boundaries by Time-of-Flight-Secondary Ion Mass Spectrometry</p> <p>Wolfram Hempel, Jonas Hanisch, Theresa Magorian Friedlmeier, Michael Powalla</p> <p>Zentrum f. Sonnenenergie- und Wasserstoff-Forschung BW, Germany</p>
M9	25	Poster	<p>(Edit Contribution Details, ID: 148)</p> <p>Parallel Ion-Electron Spectrometry (PIES): Merging strengths of Secondary Ion Mass Spectrometry and Transmission Electron Microscopy</p> <p>Alisa Pshenova, Tom Wirtz, Santhana Eswara</p> <p>Luxembourg Institute of Science and Technology (LIST)</p>
M9	26	Poster	<p>(Edit Contribution Details, ID: 161)</p> <p>SIMS and Resonant Laser-SNMS measurements on Pyrite Particles Contacted with ^{239}Pu</p> <p>Felix Berg, Daniela Schönenbach, Pascal Schönberg, Markus Breckheimer, Raphael Haas, Samer Amayri, Tobias Reich</p> <p>Johannes Gutenberg-Universität Mainz, Germany</p>
M9	27	Poster	<p>(Edit Contribution Details, ID: 140)</p> <p>Characterization of DLC using ToF-SIMS and RBS/ERD</p> <p>Alexandre Felten, Julien L. Colaux, Pierre Louette</p> <p>SIAM platform, University of namur, Namur, Belgium</p>
M9	28	Poster	<p>(Edit Contribution Details, ID: 158)</p> <p>Setup and Characterization of a Resonant Laser-SNMS System for Conductive and Non-Conductive Plutonium Samples</p> <p>Daniela Schönenbach, Pascal Schönberg, Felix Berg, Raphael Haas, Tobias Reich</p> <p>Johannes Gutenberg-University Mainz, Germany</p>
M9	29	Poster	<p>(Edit Contribution Details, ID: 147)</p> <p>ToF-SIMS, XPS and XRR study of $Al:HfO_2/TiN$ interface for MIM capacitors</p> <p>Enrica Ravizza¹, Rossella Piagge¹, Simona Spadoni¹, Silvia Vangelista¹, Alessio Lamperti²</p> <p>¹ST Microelectronics, Via C. Olivetti 2, Agrate Brianza, MB I-20864, Italy; ²CNR-IMM - MDM Laboratory, Via C. Olivetti 2, Agrate Brianza, MB I-20864, Italy</p>
M9	30	Poster	<p>(Edit Contribution Details, ID: 121)</p> <p>ToFSIMS and other surface spectroscopies applied to the study of ancient artefacts: further studies on Alexandrian tetradrachms from the time of the Julio-Claudian dynasty</p> <p>Rana N.S. Sodhi¹, Peter Brodersen¹, Sal Boccia¹, Amandina Anastassiades², Cristiana Zaccagnino³</p> <p>¹Ontario Centre for the Characterisation of Advanced Materials, University of Toronto, Canada; ²Dept. Art History & Art Conservation, Queen's University, Canada; ³Classics/Languages, Literatures & Cultures, Queen's University, Canada</p>
M9	31	Poster	<p>(Edit Contribution Details, ID: 229)</p> <p>Diffusion Experiments and Phase Formation in the Al-Cu-System with ToF-SIMS and XRD</p> <p>Andreas Amsüss¹, Werner Robl², Herbert Hutter¹</p> <p>¹TU Wien, Austria; ²Infineon Technologies AG, Regensburg, Germany</p>
M9	32	Poster	<p>(Edit Contribution Details, ID: 236)</p> <p>FIBSIMS investigation of Solid State Lithium battery failure</p> <p>Federico Pesci, Rowena Brugge, Orla Hekselman, Andrea Cavallaro, <u>Richard John Chater</u>, Ainara Aguadero</p> <p>Imperial College London, United Kingdom</p>
M9	33	Poster	<p>(Edit Contribution Details, ID: 176)</p> <p>ToF-SIMS Study on Li Metal Electrodes</p> <p>Anja Henss, Svenja Otto, Urmimala Maitra, Marcus Rohnke, Daniel Schroeder, Juergen Janek</p> <p>Institute of Physical Chemistry and Centre for Material Research, Justus Liebig University of Giessen</p>

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M9	34	Poster	<p>Detailed analysis of organometallic perovskite solar cells with ToF-SIMS using four different sputter sources</p> <p>Jonas Hanisch, Tina Wahl, Moritz Schultes, Wolfram Hempel, Erik Ahlswede Zentrum für Sonnenenergie- und Wasserstoff-Forschung Baden-Württemberg (ZSW), Germany</p>
M9	35	Poster	<p>(Edit Contribution Details, ID: 170)</p> <p>Unsupervised analysis of full hybrid OLEDs by ToF-SIMS coupled with wavelet-PCA</p> <p>Céline Noël¹, Nunzio Tuccitto², Yan Busby¹, Manuel Auer³, Antonino Licciardello², Emil List-Kratochvil⁴, Laurent Houssiau¹</p> <p>¹University of Namur, Belgium; ²University of Catania, Italy; ³Institut für Oberflächentechnologien und Photonik, Austria; ⁴Humboldt-Universität zu Berlin, Germany</p>
M9	36	Poster	<p>(Edit Contribution Details, ID: 106)</p> <p>Analysis of deuterium in austenitic stainless steel AISI 304L by Time-of-Flight Secondary Ion Mass Spectrometry</p> <p>Andreas Röhsler, Oded Sobol, Thomas Böllinghaus, Wolfgang E.S. Unger Federal Institute for Materials Research and Testing, Germany</p>
M9	37	Poster	<p>(Edit Contribution Details, ID: 227)</p> <p>COMPOSITION AND MORPHOLOGY OF THE SURFACE OF CaF₂ WITH NANOSIZED Si PHASES</p> <p>Dilnoza Artikbaevna Tashmukhamedova, Maxsuna Baxodirovna Yusupjonova, Gulmira Xolmuratovna Allayorova, Baltohadja Ermatovich Umirzakov Tashkent state technical university, Uzbekistan</p>
M9	38	Poster	<p>(Edit Contribution Details, ID: 179)</p> <p>Determination of trace concentrations of transmuted stable nuclides in neutron fluence detectors using SIMS</p> <p>Jan Lorincik, Petr Homola, Ladislav Viererbl, Vit Klupak, Zdena Lahodova, Klara Rezankova, Kristina Sihelska Research Center Rez, Czech Republic</p>
M9	39	Poster	<p>(Edit Contribution Details, ID: 109)</p> <p>Sputtering derived artefacts in austenitic steel during Time-of-Flight Secondary Ion Mass Spectrometry analyses</p> <p>Andreas Röhsler, Oded Sobol, Gert Nolze, Thomas Böllinghaus, Wolfgang Unger BAM - Federal Institute for Materials Research and Testing, Germany</p>
M9	40	Poster	<p>(Edit Contribution Details, ID: 219)</p> <p>Focused ion beam specimen preparation of microtensiles for unirradiated and irradiated ferritic steel</p> <p>Claudia Gasparrini¹, Albert D Smith², Jack Donoghue², Richard J Chater¹, Matthew Rogers², Nick Riddle³, Philipp Frankel², M Grace Burke², Mark R Wenman¹</p> <p>¹Imperial College London, United Kingdom; ²Manchester University, United Kingdom; ³Rolls-Royce, United Kingdom</p>
M9	41	Poster	<p>(Edit Contribution Details, ID: 185)</p> <p>ToF-SIMS characterization of conductive molecular wires assembled onto oxide substrates</p> <p>Alessandra Bombace, Nunzio Tuccitto, Andrea Valenti, Alberto Torrisi, Antonino Licciardello University of Catania, Italy</p>
M9	42	Poster	<p>(Edit Contribution Details, ID: 232)</p> <p>Advanced SIMS analysis to enable next generation Additive Manufacturing</p> <p>Gustavo F. Trindade, Richard Hague, Clive J. Roberts University of Nottingham, United Kingdom</p>
M9	43	Poster	<p>(Edit Contribution Details, ID: 230)</p> <p>3D Localization of Spinel and Sodium Contamination in Alumina by TOF-SIMS</p> <p>Petr Bábor^{1,2}, Radek Holeňák¹, Tomáš Spusta², Michal Potoček^{1,2}, David Salamon²</p> <p>¹Institute of Physical Engineering, Faculty of Mechanical Engineering, Brno University of Technology, Technická 2896/2, Brno, 616 69, Czech Republic; ²CEITEC - Central European Institute of Technology, Brno University of Technology, Brno, 616 00, Czech Republic</p>
M9	44	Poster	<p>(Edit Contribution Details, ID: 151)</p> <p>SIMS investigation of silver dendrites formed by electromigration</p> <p>Jonas Neumeier, Bjoern Luerßen, Matthias Elm, Jürgen Janek, Marcus Rohnke Justus-Liebig University Giessen, Germany</p>
M9	45	Poster	<p>(Edit Contribution Details, ID: 131)</p> <p>TOF SIMS⁵ application for quantitative analyses of water in geological objects</p> <p>Sergei Simakin¹, Alexander Rudy^{1,2}, Evgenii Kozlov²</p> <p>¹Institute of Physics and Technology of RAS, Yaroslavl Branch, Russian Federation; ²P.G. Demidov Yaroslavl State University, Russian Federation</p>

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M9	46	Poster	<p>The effect of carbon and boron content on environmental cracking resistance along grain boundaries in Co/Ni superalloys.</p> <p>Lucy Rhiannon Reynolds, Bantounas Ioannis, Chater Richard, Hardy Mark, Dye David Imperial College London, United Kingdom</p>
M9	47	Poster	<p>(Edit Contribution Details, ID: 216)</p> <p>Universal Indicator Paper as Model System for Hybrid-SIMS Experiments</p> <p>Daniel Breitenstein¹, Lamann Karsten^{1,3}, Dinter Adelina-Elisa³, Tallarek Elke¹, PirkI Alexander², Niehuis Ewald², Karst Uwe³, Hagenhoff Birgit¹</p> <p>¹Tascon GmbH, Mendelstraße 17, 48149 Münster; ²IONTOF GmbH, Heisenbergstr. 15, 48149 Münster; ³Institute of Inorganic and Analytical Chemistry, University of Münster, Corrensstr. 28/30, 48149 Münster</p>
M9	48	Poster	<p>(Edit Contribution Details, ID: 103)</p> <p>Using TOF-SIMS for researching nanoparticles</p> <p>Tatyana Kravchuk Technion - Israel Institute of Technology, Israel</p>
M9	49	Poster	<p>(Edit Contribution Details, ID: 104)</p> <p>Spatially resolved measurement of surface area changes in laser-structured dye / TiO₂ nanoparticles films employing time-of-flight secondary ion mass spectrometry</p> <p>Lina Schade^{1,2}, Steffen Franzka^{1,2,3}, Elke Tallarek⁴, Sven Kayser⁵, Nils Hartmann^{1,2,3}</p> <p>¹Department of Chemistry, University of Duisburg-Essen, Germany; ²Center for Nanointegration Duisburg-Essen (CENIDE), University of Duisburg-Essen, Germany; ³Interdisciplinary Center for Analytics on the Nanoscale (ICAN), University of Duisburg-Essen, Germany; ⁴Tascon GmbH, Münster, Germany; ⁵IONTOF GmbH, Münster Germany</p>
M9	50	Poster	<p>(Edit Contribution Details, ID: 226)</p> <p>ELECTRONIC AND OPTICAL PROPERTIES OF NiSi₂/Si NANOFILMS</p> <p>Dilnoza Artikbaevna Tashmukhamedova, Jahongirbek Shuxratak ugli Sodiqjanov, Nodira Moylievna Mustafojeva, Allanazar Qarshievich Tashatov Tashkent state technical university, Uzbekistan</p>
M9	51	Poster	<p>(Edit Contribution Details, ID: 134)</p> <p>Migration of Ni from sub-nanometric layer to thicker oxide layers : attempts to access to the composition profile by ToF-SIMS</p> <p>Justine Mathilde Voronkoff¹, Thierry Cretin², Hervé Montigaud¹</p> <p>¹Surface du Verre et Interfaces UMR 125 CNRS/Saint-Gobain, Aubervilliers, France; ²Saint-Gobain Recherche, Aubervilliers, France</p>
M9	52	Poster	<p>(Edit Contribution Details, ID: 155)</p> <p>Surface analysis of Representative Test (nano)-Materials distributed by the JRC Nanomaterials Repository.</p> <p>Giulio Cotogno, Giaco Ceccone, Douglas Gilliland, Dora Mehn, Jessica Ponti European Commission, Joint Research Centre (JRC), JRC Directorate F - Health, Consumers and Reference Materials, Unit F2 Consumers Products Safety, TP 125, via Enrico Fermi 2749, 21027 Ispra (VA) - Italy</p>
M9	53	Poster	<p>(Edit Contribution Details, ID: 212)</p> <p>Optimisation of sample preparation for characterisation of engineered nanomaterials using ToF-SIMS under close to real-life conditions</p> <p>Yves U. Hachenberger¹, Philipp Reichardt¹, Jutta Tentschert¹, Harald Jungnickel¹, Peter Laux¹, Pietro Benettoni², Stephan Wagner², Hryhoriy Stryhanyuk², Giacomo Ceccone³, Douglas Gilliland³, Markus Schneider⁴, Kaija Schäpe⁴, Thomas Heinrich⁴, Wolfgang E.S. Unger⁴, Andreas Luch¹</p> <p>¹German Federal Institute for Risk Assessment, Germany; ²Helmholtz Center for Environmental Research, Leipzig, Germany; ³European Commission Joint Research Centre, Ispra, Italy; ⁴Federal Institute for Materials Research and Testing, Berlin, Germany</p>
M9	54	Poster	<p>(Edit Contribution Details, ID: 142)</p> <p>Study on protein adsorption to thin layers of poly(butyl methacrylate)</p> <p>Kamil Awsiuk¹, Joanna Raczowska¹, Yuriy Stetsyshyn², Natalia Janiszewska¹, Ostap Lishchynskyi², Katarzyna Gajos¹, Andrzej Budkowski¹</p> <p>¹Smoluchowski Institute of Physics, Jagiellonian University, Poland; ²Lviv Polytechnic National University, Ukraine</p>
M9	55	Poster	<p>(Edit Contribution Details, ID: 138)</p> <p>Molecular ToF-SIMS Imaging of Artificial Lipid Membranes Using a Discriminant Analysis Based Algorithm</p> <p>Rainer Kassenböhmer¹, Marcel Heeger¹, Mridula Dwivedi², Martin Koersgen¹, Bonnie J. Tyler¹, Hans-Joachim Galla², Heinrich F. Arlinghaus¹</p> <p>¹Physikalisches Institut, Westfälische Wilhelms-Universität Münster, Germany; ²Institut für Biochemie, Westfälische Wilhelms-Universität Münster, Germany</p>
M9	56	Poster	<p>(Edit Contribution Details, ID: 122)</p> <p>Cluster SIMS of Liquid and Soft Materials with 3D Carbon Nano-frames</p>

Stanislav V. Verkhoturov^{1,2}, Dmitriy S. Verkhoturov², Jian Tan³, Gang Yang³, Jevon Phandi³, Choongho Yu³, Andreas A. Polycarpou³, Emile A. Schweikert²

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M9	(Edit Contribution Details, ID: 215)
57	Detection of Inorganic Nanoparticles in Lung Tissue Sections
Poster	Veith Lothar^{1,3}, Daniel Breitenstein¹, Vennemann Antje², Hagenhoff Birgit¹, Wiemann Martin² ¹ Tascon GmbH, Mendelstraße 17, 48149 Münster; ² IBE Institute for Lung Health gGmbH, Mendelstrasse 11, 48149 Münster; ³ meanwhile: Max Planck Institute for Polymer Research, Ackermannweg 10 - D-55128 Mainz

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58	Chemical Mapping of Drug Permeation through Microneedle Channels using ToF-SIMS
Poster	Akmal Sabri¹, Jane Ogilvie², John McKenna³, Volha Shpadaruk³, Joel Segal⁴, David Scurr¹, Maria Marlow¹ ¹ Advanced Materials and Healthcare Technologies Group, School of Pharmacy, University of Nottingham, NG7 2RD, Nottingham, UK; ² Walgreens Boots Alliance, Thane Road, Nottingham, NG90 1BS; ³ Leicester Royal Infirmary, University Hospitals of Leicester Dermatology Department, Infirmary Square, Leicester LE1 5WW; ⁴ Department of Mechanical, Materials and Manufacturing Engineering, Faculty of Engineering, University of Nottingham, Nottingham, NG8 1BB

M9	(Edit Contribution Details, ID: 192)
59	Three-dimensional reconstruction of a structured organic multilayer system using a TOF-SIMS and atomic force microscopy
Poster	Tobias Heckhoff, Andreas Wucher Universität Duisburg-Essen, Germany

M9	(Edit Contribution Details, ID: 225)
60	NanoSIMS combined with electron microscopy and X-ray techniques to study the impact of cadmium on carbon assimilation in the mixotrophic micro-alga <i>Chlamydomonas reinhardtii</i>
Poster	Florent Penen¹, Marie-Pierre Isaure¹, Dirk Dobritzsch², Hiram Castillo-Michel³, Etienne Gontier⁴, Philippe Le Coustumer^{1,4,5}, Julien Malherbe¹, Dirk Schaumlöffel¹ ¹ CNRS / Université de Pau et des Pays de l'Adour / E2S UPPA, Institut des Sciences Analytiques et de Physico-Chimie pour l'Environnement et les Matériaux, UMR 5254, 64000 Pau, France; ² Martin-Luther-Universität Halle-Wittenberg, Institute for Biochemistry and Biotechnology, Plant Biochemistry, Tanford Protein Centre, Kurt-Mothes-Str. 3a, 06120 Halle (Saale), Germany; ³ ID21 Beamline, European Synchrotron Radiation Facility (ESRF), BP220, 38043 Grenoble, France; ⁴ Université de Bordeaux, Bordeaux Imaging Center UMS 3420 CNRS - US4 INSERM, Pôle d'imagerie électronique, 146 rue Léo Saignat, 33076 Bordeaux, France; ⁵ Université de Bordeaux, UF Sciences de la Terre et Environnement, Allée G. Saint-Hillaire, 33615 Pessac, France

M9	(Edit Contribution Details, ID: 205)
61	The physicochemical fingerprint of <i>Necator americanus</i>
Poster	Veeran Chauhan, David Scurr, Thomas Christie, Gary Telford, Jonathan Aylott, David Pritchard School of Pharmacy, University of Nottingham, NG7 2RD, United Kingdom

M9	(Edit Contribution Details, ID: 235)
62	Visualizing Carbon and Nitrogen exchange at the cellular scale in the ectomycorrhizal symbiosis using NanoSIMS
Poster	Werner Mayerhofer¹, Arno Schintlmeister^{1,2}, Marlies Dietrich¹, Stefan Gorka¹, Siegfried Reipert³, Marieluise Weidinger³, Andreas Richter¹, Dagmar Woebken¹, Christina Kaiser¹ ¹ Department of Microbiology and Ecosystem Science, University of Vienna, Austria; ² Large-Instrument Facility for Advanced Isotope Research, University of Vienna, Austria; ³ Core Facility of Cell Imaging and Ultrastructure Research (CIUS), University of Vienna, Austria

M9	(Edit Contribution Details, ID: 128)
63	Using room temperature and cryogenic 3D OrbiSIMS to understand the regulation of <i>Drosophila</i> cuticular lipids
Poster	Clare L. Newell^{1,2}, Ian S. Gilmore², Alex P. Gould¹ ¹ The Francis Crick Institute, 1 Midland Road, London, NW1 1AT, UK; ² National Centre for Excellence in Mass Spectrometry Imaging, National Physical Laboratory, Teddington, TW11 0LW, UK

M9	(Edit Contribution Details, ID: 193)
64	Specific target imaging of lipids and proteins of cellular plasma membrane using nanoSIMS
Poster	Paola Agüi-Gonzalez¹, Nhu T.N Phan^{1,2}, Silvio O. Rizzoli¹ ¹ Institute of Neuro- and Sensory Physiology, University of Goettingen Medical Center, Goettingen, Germany; ² Department of Chemistry and Molecular Biology, University of Gothenburg, Gothenburg, Sweden

[\(Edit Contribution Details, ID: 154\)](#)

M9	65	Poster	<p>Characterization of animal fibre: investigation and differentiation of different fibres species using secondary ion mass spectrometry</p> <p>Jean-Luc Vorng¹, Elzbieta Gurdak¹, Spencer, A Thomas¹, James, H Hinchliffe², David, K Mallin³, Ian, S Gilmore¹</p> <p>¹National Physical Laboratory, Hampton road Teddington TW11 0LW United kingdom; ²Z. Hinchliffe & sons LTD. Hartcliffe Mills Denby Dale, Huddersfield HD 8 8QL United Kingdom; ³Cashmere Fibres International Limited, Park view Mills, Raymond Street, West Yorkshire, BD5 8 DT, England</p>
M9	66	Poster	<p>(Edit Contribution Details, ID: 174)</p> <p>Isotopic Labelling of Biological Materials for Secondary Ion Mass Spectrometry Imaging</p> <p>Selda Kabatas^{1,2}, Kim-Ann Saal², Felipe Opazo^{1,2}, Ulf Diederichsen³, Silvio O. Rizzoli^{1,2}</p> <p>¹Center for Biostructural Imaging of Neurodegeneration, University Medical Center Göttingen, Germany; ²Department of Neuro- and Sensory Physiology, University Medical Center Göttingen, Germany; ³Institute of Organic and Biomolecular Chemistry, Georg-August-University Göttingen, Germany</p>
M9	67	Poster	<p>(Edit Contribution Details, ID: 210)</p> <p>Classification of engineered Titania Nanomaterials via Surface Analysis using Principal Component Analysis (PCA) assisted Time-of-Flight Secondary Ion Mass Spectrometry (ToF-SIMS)</p> <p>Markus Schneider, Thomas Heinrich, Kaija Schaepe, Wolfgang E. S. Unger</p> <p>BAM, Department 6.1 – Surface Analysis and Interfacial Chemistry, Unter den Eichen 44-46, 12203 Berlin</p>
M9	68	Poster	<p>(Edit Contribution Details, ID: 183)</p> <p>Extracting latent chemical information from ToF-SIMS data arising from chemical imaging</p> <p>Nunzio Tuccitto, Alessandra Bombace, Alberto Torrisi, Giacomo Capizzi, Antonino Licciardello</p> <p>University of Catania, Italy</p>
M9	69	Poster	<p>(Edit Contribution Details, ID: 207)</p> <p>The Use of PCA as a Daily Analysis Tool in ToF-SIMS</p> <p>Birgit Hagenhoff¹, Danica Heller², Rik ter Veen¹</p> <p>¹Tascon GmbH, Münster, Germany; ²Infineon Technologies, Warstein, Germany</p>
M9	70	Poster	<p>(Edit Contribution Details, ID: 249)</p> <p>Spectra Superposition – A tool to simplify peak selection in sets of high resolution spectra</p> <p>Henrik Arlinghaus¹, Daniel Graham², Ewald Niehuis¹</p> <p>¹IONTOF GmbH, Germany; ²University of Washington</p>
M9	71	Poster	<p>(Edit Contribution Details, ID: 253)</p> <p>Identification of Unknown Contaminants in Industrial Applications Using MS/MS in Combination with High Resolution Mass</p> <p>Alexander Pirkl, Sven Kayser, Henrik Arlinghaus, Julia Zakel, Derk Rading, Rudolf Moellers, Ewald Niehuis</p> <p>IONTOF GmbH, Germany</p>
M9	72	Poster	<p>The contribution has been withdrawn.</p> <p>ToF-SIMS ion comparison study of untreated and PZ-128 treated cryofixed human coronary artery endothelial cells</p> <p>Michael Chrubasik^{1,2,5}, Rachel Wood¹, Robert Liskamp³, Ian Gilmore⁴, Alastair Florence^{1,2}, Margaret Cunningham¹, Blair Johnston^{1,2,5}</p> <p>¹University of Strathclyde, Strathclyde Institute of Pharmacy & Biomedical Sciences, Glasgow, United Kingdom; ²University of Strathclyde, Future Manufacturing Hub CMAC, Glasgow, United Kingdom; ³Glasgow University, School of Chemistry, Glasgow, United Kingdom; ⁴NPL Scotland, Glasgow, United Kingdom; ⁵NPL Teddington, Teddington, United Kingdom</p>